

Notice of References Cited

Application/Control No.	Applicant(s)/Patent Under	
09/895,689	Reexamination LUO, HUITAO	
Examiner	Art Unit	
Kevin Sianachin	2623 Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,539,523	07-1996	Nakai et al.	358/296
	В	US-6,587,225	07-2003	Sakatani et al.	358/1.9
	С	US-2002/0172419	11-2002	Lin et al.	382/167
	D	US-6,748,097	06-2004	Gindele et al.	382/112
	E	US-5,528,339	06-1996	Buhr et al.	355/32
	F	US-5,130,935	07-1992	Takiguchi, Hideo	382/167
	G	US-			
	π	US-			
	_	US-			
	J	US-		·	
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р			-		
	ø			-		
	R			-		
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Materka, A. and Strzelecki, M., "Texture Analysis Methods - A Review", Technical University of Lodz, Institute of Electronics, COST B11 Report, Brussels, 1998
	V	Sonka, Hlavac, and Boyle, "Image Processing, Analysis, and Machine Vision", 2nd Edition, © 1999, Brooks/Cole Publishing Company, pp. 59-60
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.